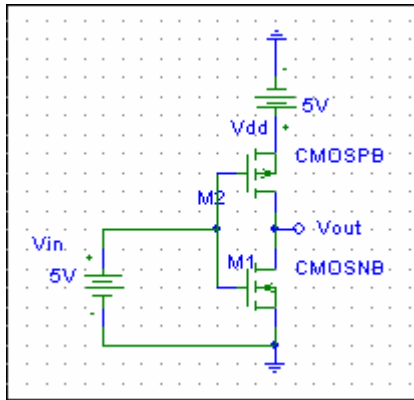


Problem 11.1

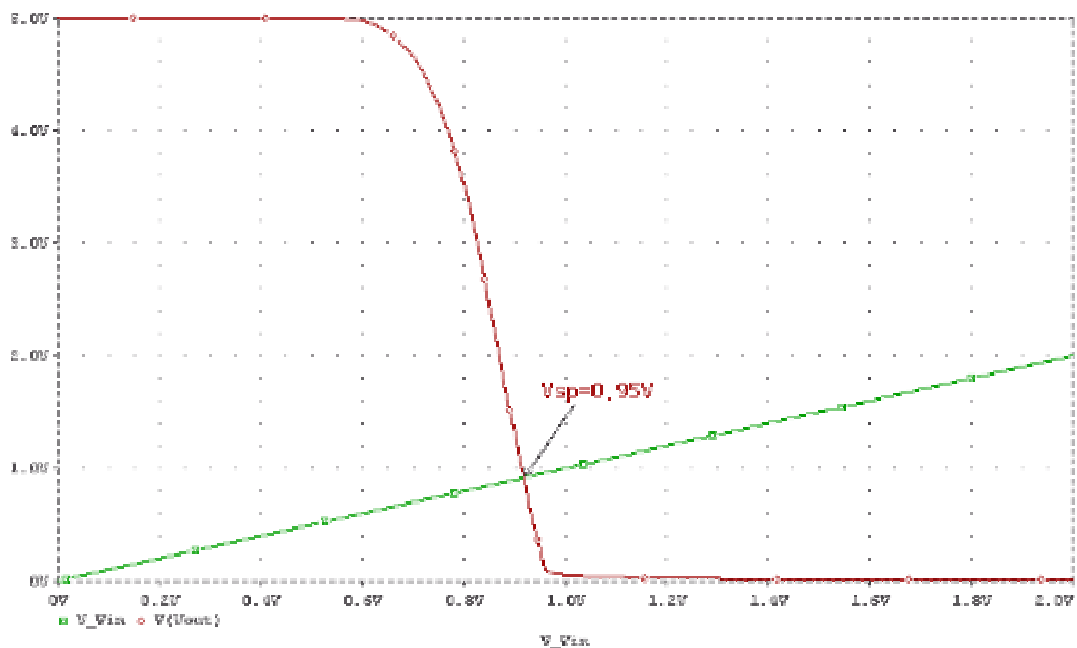
From equation (11.4), with V_{SP} approximately equal to V_{THN} , β_n should be far larger than β_p . In a basic inverter, for both NMOS and PMOS, the length of devices is same and $W_n = 400\mu m$, $W_p = 3\mu m$. Assume $K_{Pn} = 3K_{Pp}$, $V_{DD} = 5V$, $V_{THN} = V_{THP} = 0.9V$,

$$V_{SP} = (20 V_{THN} + V_{DD} - V_{THP}) / (1+20) \approx 1.05V$$



PMOS: 3/2, NMOS: 400/2

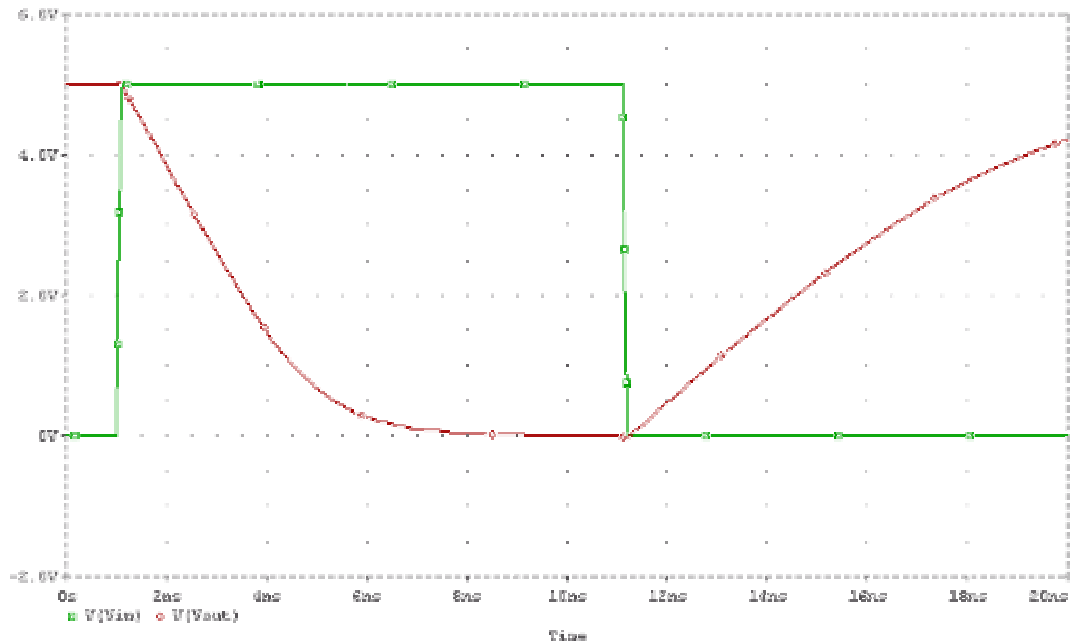
While doing simulation, need to use the DC sweep to observe the Vsp.



Problem 11.2

With $W = 10\mu m$ and a load capacitance of $1pF$, $C_{tot} = 1pF + 2 \times 10 \times 2 \times 800aF = 1.032pF$.
 $R_{n1} = 12K\Omega \times 2/10 = 2.4K\Omega$, $R_{p2} = 7.2K\Omega$. The propagation delay times are
 $t_{PHL} = 2.4k\Omega \times 1.032pF \approx 2.5ns$, $t_{PLH} = 7.2k\Omega \times 1.032pF \approx 7.43ns$

Vin is Vpulse, whose parameters are: 0 5 1ns 0 0 10ns 20ns (not unique, you can use whatever proper parameters for the Vin)



Problem 11.3

For minimum size inverter, $t_{PHL} + t_{PLH} = 160k \times C_{ox} = 160k\Omega \times 4.8fF = 768ps$. Using 31 inverters, the oscillation frequency is
 $f_{osc} = 1/(31 \times 768ps) \approx 42MHz$.

Problem 12.1

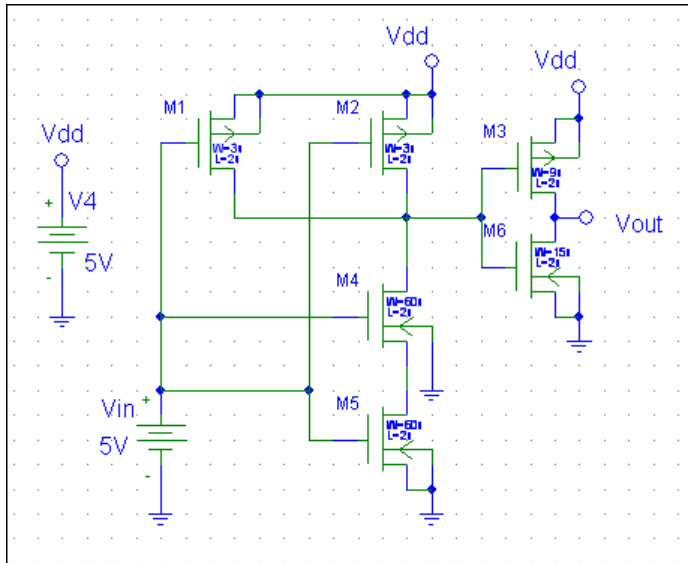
Solution: a) Design and hand-cal: The 2-input CMOS AND gate circuit diagram is shown below which consists of two parts NAND and INVERTOR cascaded:

To find V_{sp} , tie input A and B together as V_{in} . From NAND gate part, ignoring the body effect, we have

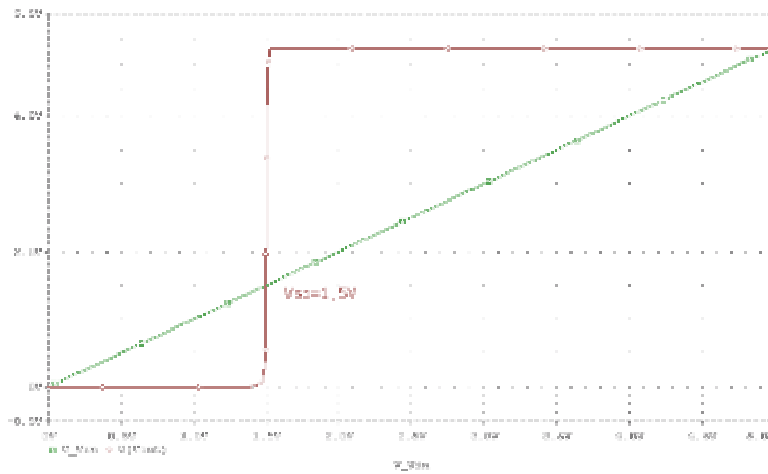
$$V_c = V_{in} = V_{sp} = \frac{\sqrt{\frac{\beta_n}{4\beta_p}} V_{thn} + (V_{dd} - V_{thp})}{1 + \sqrt{\frac{\beta_n}{4\beta_p}}} \quad (12.1a)$$

$$V_{out} = V_c = V_{sp} = \frac{\sqrt{\frac{\beta_n}{\beta_p}} V_{thn} + (V_{dd} - V_{thp})}{1 + \sqrt{\frac{\beta_n}{\beta_p}}} \quad (12.1b)$$

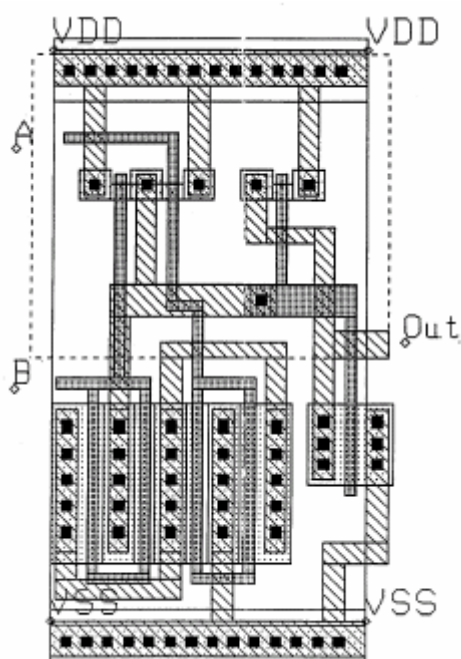
$V_{thn}=0.83V$, $V_{thp}=0.91V$, choosing all the length of CMOS $L=2\mu$, all $W_p=3\mu$ for p-channel. Let both V_{sp} expression equals to $1.5V$, $\implies W_4=W_5=60\mu$, $W_6=15\mu$.



Again, While doing simulation to observe V_{sp} , let $V_a=V_b=V_{in}$, and DC sweep V_{in} .



LAYOUT:



Problem 12.3

Solution: For N-input NOR gate, we have:

$$t_{PLH} = NRp(Coutp / N + Ncoutn + Cload) + 0.35RpCinp(N - 1)^2 \quad (12.3a)$$

$$t_{PHL} = (Rn / N)(Ncoutn + Coutp / N + Cload) \quad (12.3b)$$

With minimum size MOSFET, $Rn=8k\Omega$, $Rp=24k\Omega$, $Coutn=Coutp=4.8fF$, $Cinp=7.2fF$. and 3input.

a) With $Cload=0$:

$$t_{PLH} = 3 \times 24k(4.8f / 3 + 3 \times 4.8f + 0) + 0.35 \times 24k \times 7.2f(3 - 1)^2 = 1394ns$$

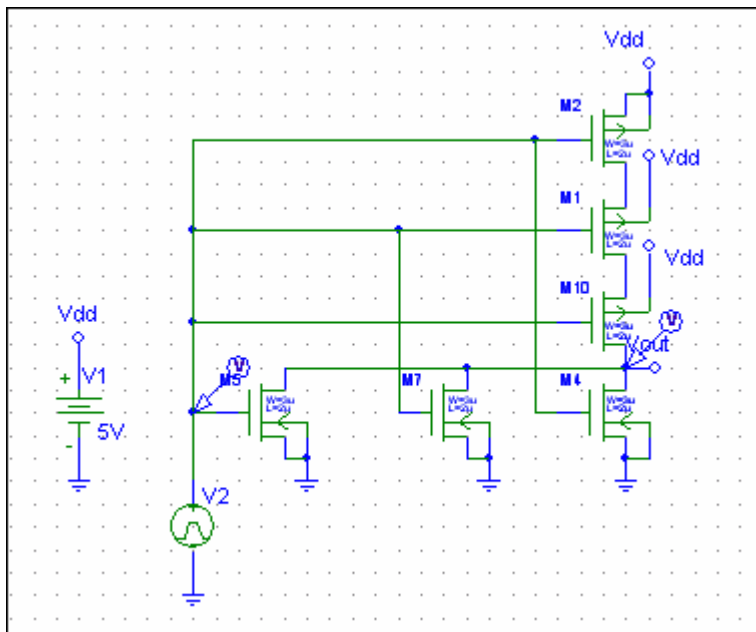
$$t_{PHL} = (8k / 3)(3 \times 4.8f + 4.8f / 3 + 0) = 42.67ps$$

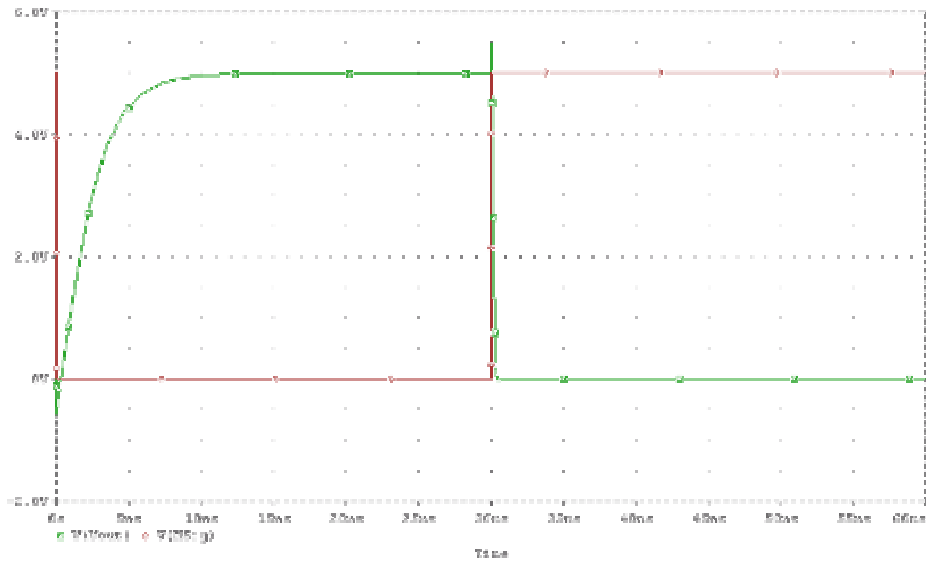
b) With $Cload=100fF$:

$$t_{PLH} = 3 \times 24k(4.8f / 3 + 3 \times 4.8f + 100) + 0.35 \times 24k \times 7.2f(3 - 1)^2 = 8.594ns$$

$$t_{PHL} = (8k / 3)(3 \times 4.8f + 4.8f / 3 + 100) = 309ps$$

It can be seen that for 3-input NOR gate, the $t_{PLH} > t_{PHL}$, while for 3-input NAND gate, the $t_{PLH} < t_{PHL}$, also that the maximum delay time of NOR is bigger than the maximum delay time of NAND. Plus we already know that NAND gate has better V_{sp} and better noise margins. That is why in CMOS digital design, the NAND gate is used most often.





From the above Figure, $t_{PLH}=5ns$. Zoom this result (see below), $t_{PHL}=160ps$

